

FIG. 1

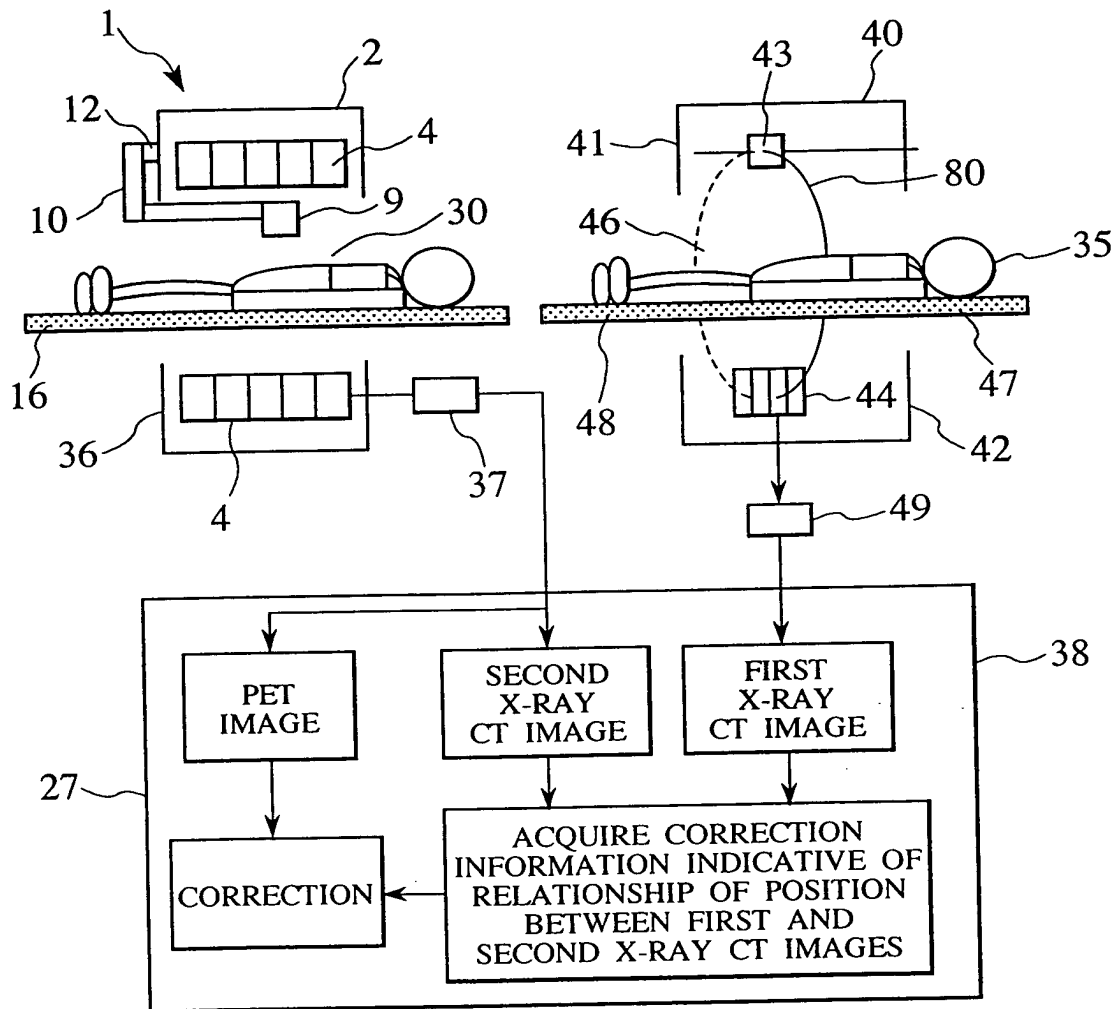


FIG. 2

FIG. 2 is a schematic diagram of a system for measuring the thickness of a substrate. The diagram shows a cross-sectional view of a substrate 1 with a top layer 2 and a bottom layer 3. A probe 4 is positioned to measure the thickness of the top layer 2. The probe 4 is connected to a control unit 19, which is part of a system 37. The system 37 also includes a display 29 and a control unit 26. The probe 4 is connected to a control unit 27, which is part of a system 38. The system 38 also includes a display 28 and a control unit 26. The probe 4 is connected to a control unit 27, which is part of a system 38. The system 38 also includes a display 28 and a control unit 26. The probe 4 is connected to a control unit 27, which is part of a system 38. The system 38 also includes a display 28 and a control unit 26.

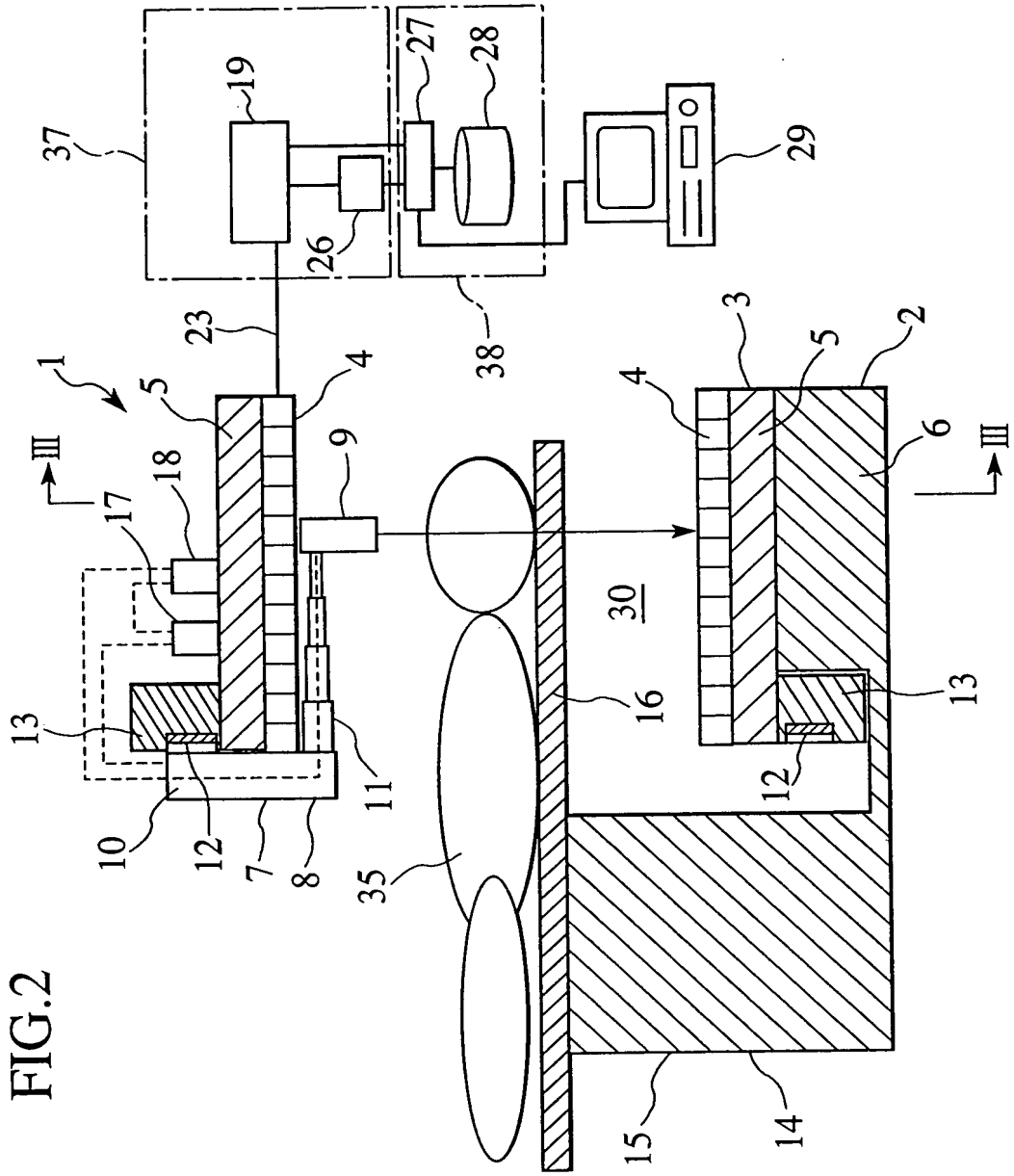


FIG.3

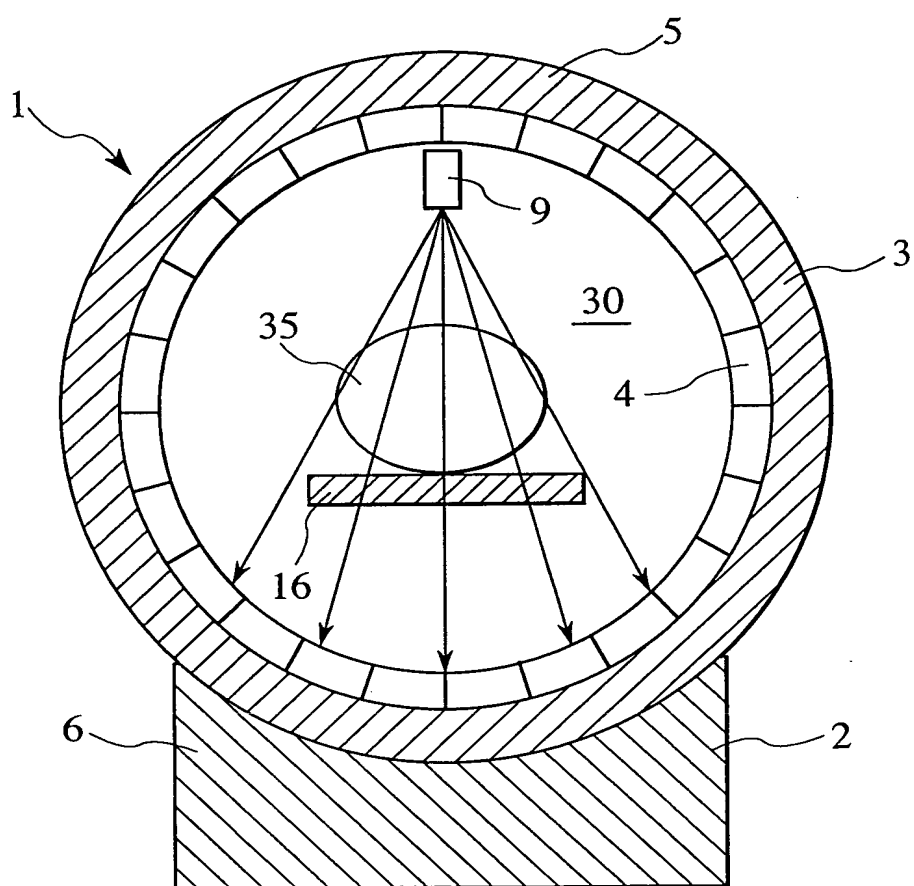


FIG.4

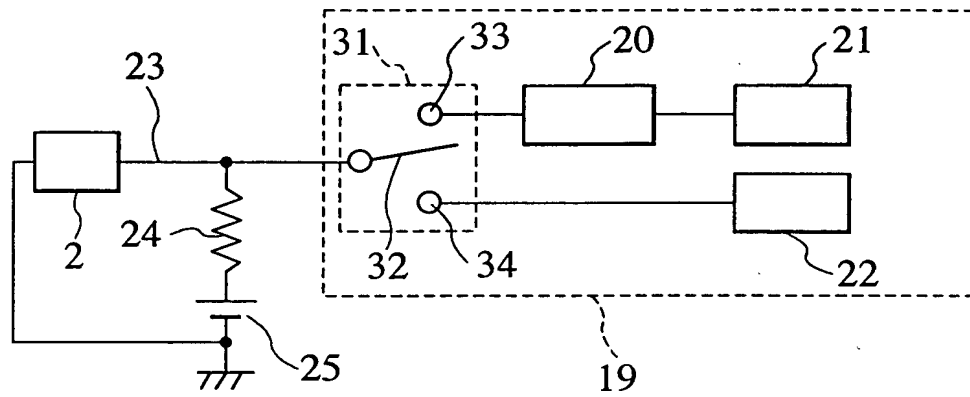


FIG.5

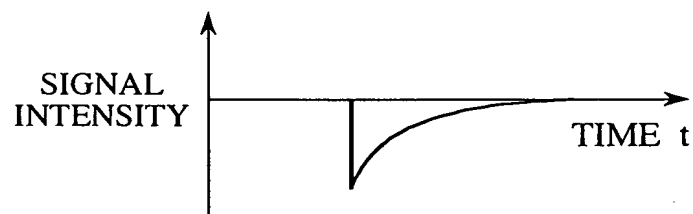


FIG.6

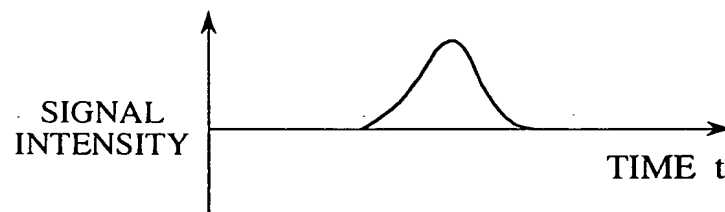


FIG.7

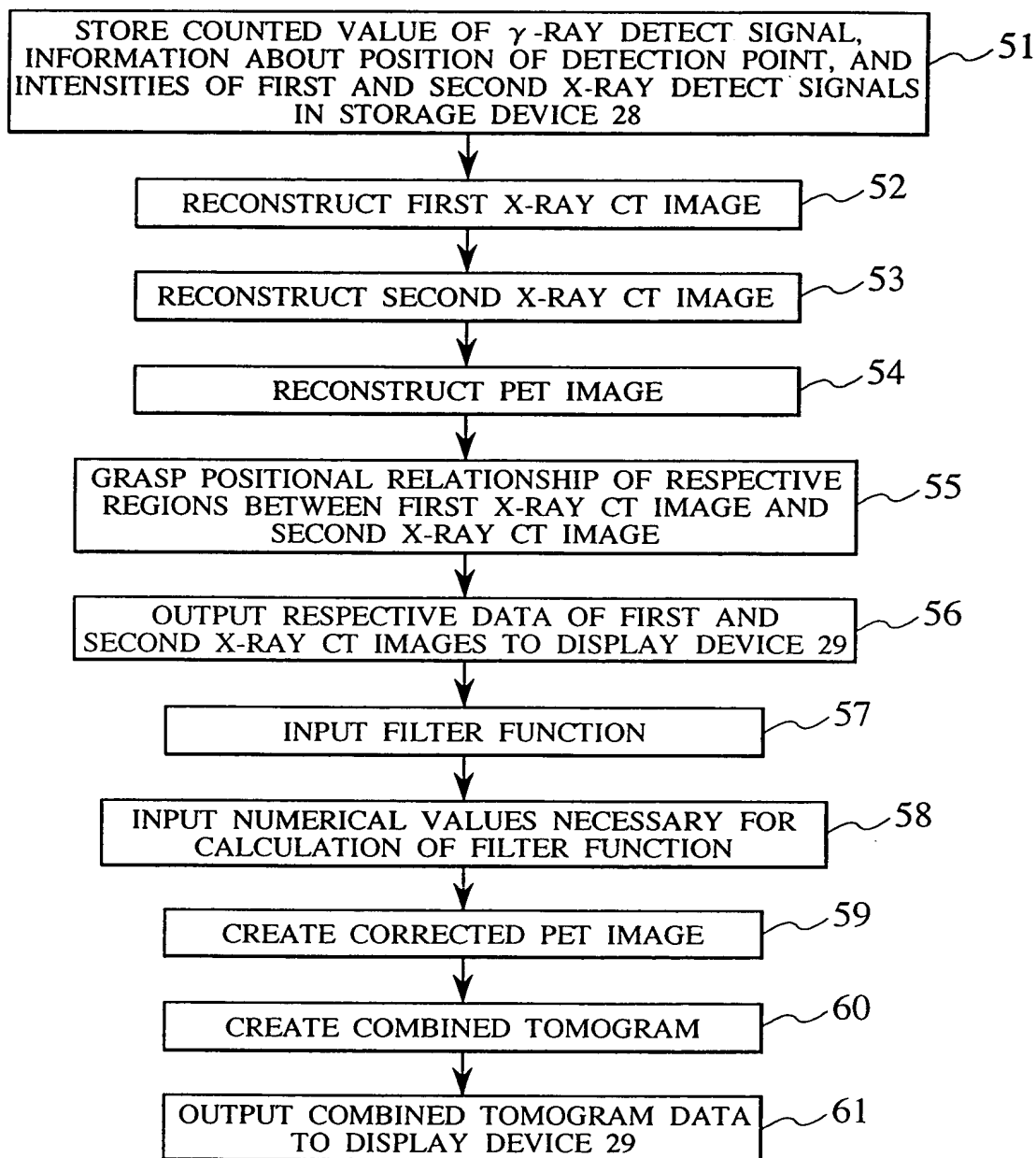


FIG.8A

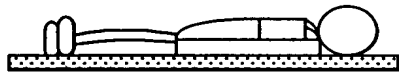


FIG.8B

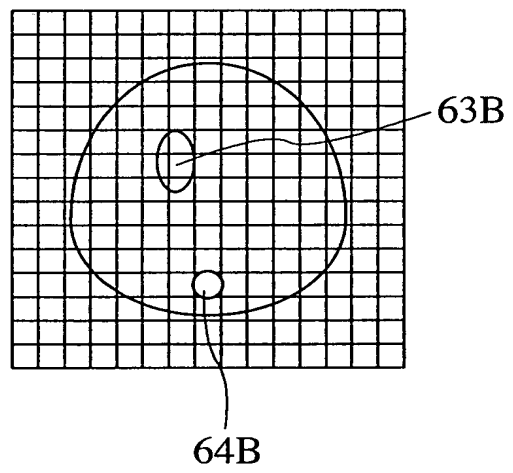
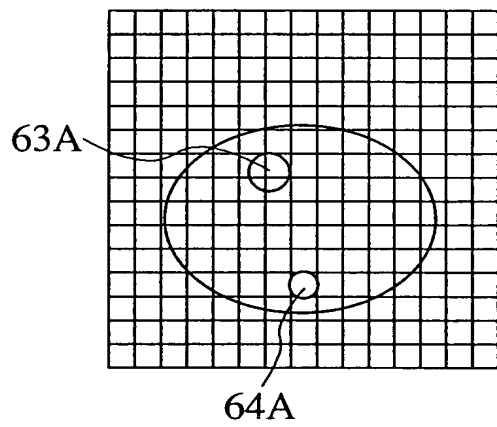
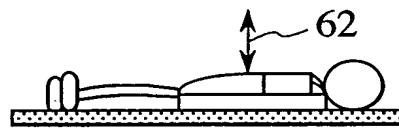


FIG. 9

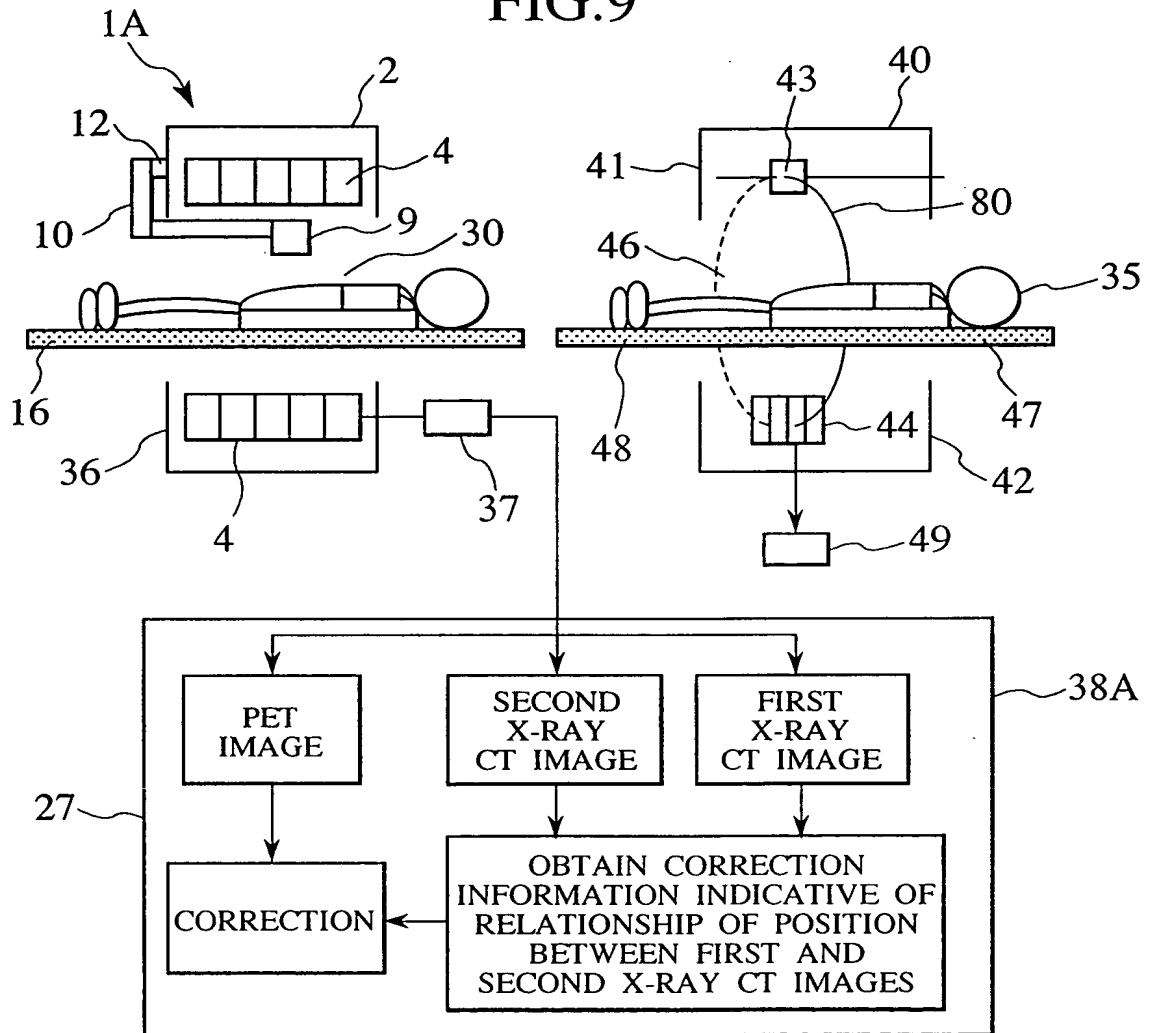


FIG.10

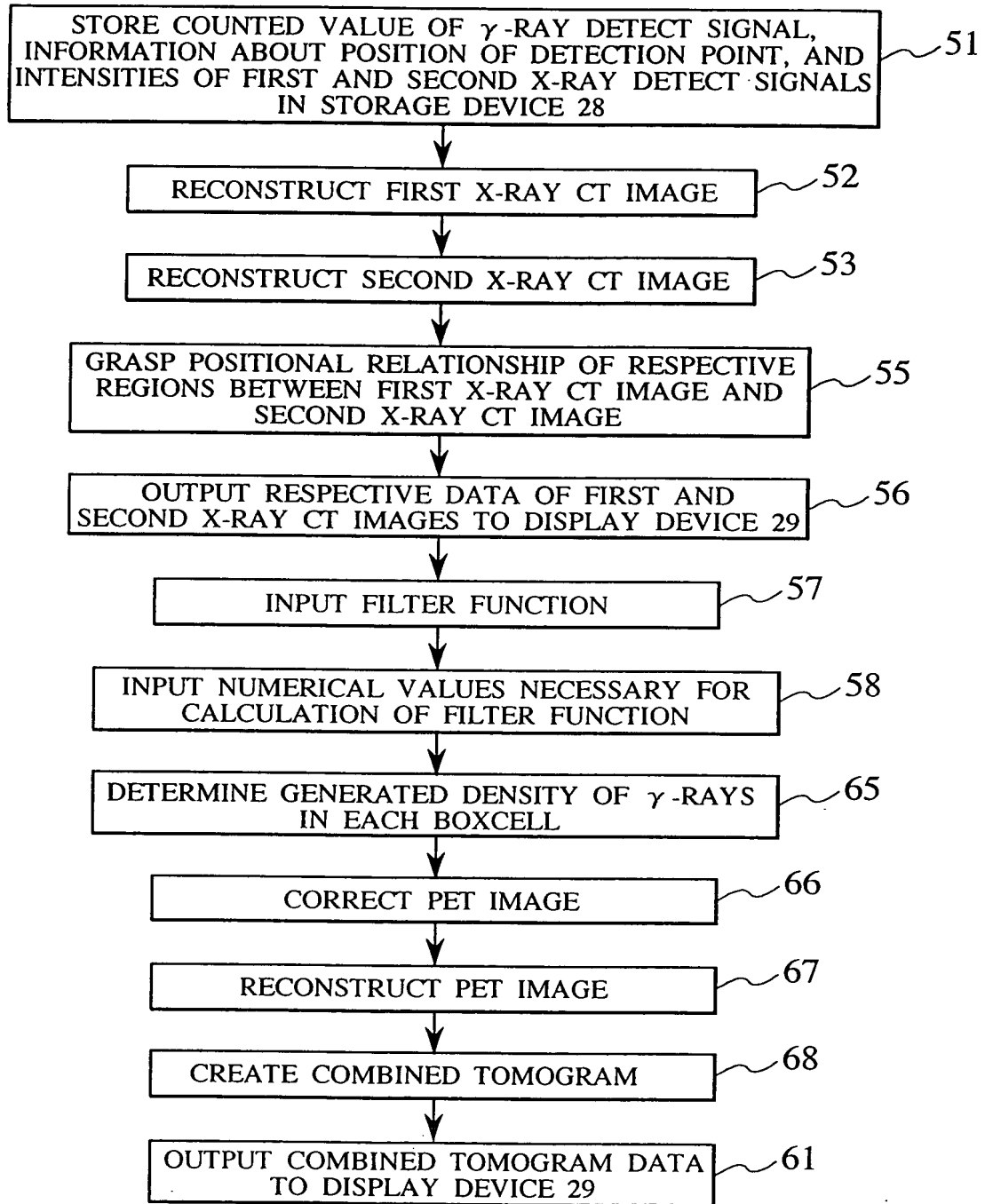




FIG.11A

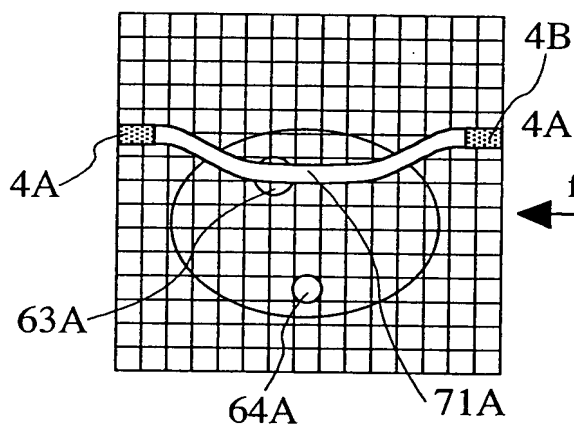


FIG.11B

